

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/535,480	ENO ET AL.	
Examiner	Art Unit	
EDMUND H. LEE	1791	

	SEARCHED				
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
264/250,238,248,247,328.1,493,494,	10/28/2007	EHL
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inventor		
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